

**AMENDMENTS TO THE CLAIMS:**

Kindly amend claims 1-4, and add claim 5, as shown below.

This listing of claims will replace all prior versions and listings of claims in the Application:

**Claim 1 (currently amended).** A ~~noncontact conductivity~~ measuring instrument for noncontact measurement of conductivity of a silicon wafer using a microwave, the ~~noncontact conductivity~~ measuring instrument characterized by including comprising:

an oscillator ~~which performs oscillation of~~ for oscillating the microwave;  
a circulator ~~which is~~ connected to the oscillator;  
a horn antenna ~~which is~~ connected to the circulator, the horn antenna transmitting the microwave to ~~a sample~~ the silicon wafer and receiving a reflected wave from a surface of the silicon wafer;

a detector ~~which is~~ connected to said circulator, the detector outputting a voltage proportional to a square of magnitude of the ~~received microwave~~ reflected wave; and  
a computer for computing means for inputting said voltage to compute computing conductivity of said silicon wafer from said voltage.

**Claim 2 (currently amended).** A ~~noncontact conductivity~~ measuring instrument according to claim 1, characterized in that wherein said circulator is in contact with connected to the oscillator through an isolator.

**Claim 3 (currently amended).** A ~~noncontact conductivity~~ measuring instrument according to claim 1, characterized in that wherein a frequency of the microwave oscillating in said oscillator is 94 GHz ~~when a silicon wafer is measured~~.

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**Claim 4 (currently amended).** A noncontact conductivity measuring instrument according to claim 2, characterized in that wherein a frequency of the microwave oscillating in said oscillator is 94 GHz ~~when a silicon wafer is measured~~.

**Claim 5 (new).** A conductivity measuring instrument for noncontact measuring of conductivity of a silicon wafer using a microwave, the measuring instrument comprising, in combination:

- an oscillator for oscillating of the microwave;
- a circulator connected to the oscillator;
- a horn antenna connected to the circulator, the horn antenna transmitting the microwave to the silicon wafer and receiving a reflected wave from a surface of the silicon wafer;
- a detector connected to said circulator, the detector outputting a voltage proportional to a square of magnitude of the reflected wave; and
- a computer for computing conductivity of said silicon wafer from said voltage.

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